

<b>Notice of References Cited</b>	Application/Control No. 10/676,474		Applicant(s)/Patent Under Reexamination VAINSTEIN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,765,152 A	06-1998	Erickson, John S.	707/9
*	B	US-6,205,549 B1	03-2001	Pravetz, James D.	713/182
*	C	US-6,351,813 B1	02-2002	Mooney et al.	713/185
*	D	US-2002/0138726 A1	09-2002	Sames et al.	713/166
*	E	US-2002/0184488 A1	12-2002	Amini et al.	713/153
*	F	US-2003/0079175 A1	04-2003	Limantsev, Alexei K.	715/500
*	G	US-6,567,914 B1	05-2003	Just et al.	713/160
*	H	US-2003/0217333 A1	11-2003	Smith et al.	715/513
*	I	US-6,782,403 B1	08-2004	Kino et al.	707/203
*	J	US-2005/0120199 A1	06-2005	Carter, Stephen R.	713/150
*	K	US-2005/0198326 A1	09-2005	Schlimmer et al.	709/229
*	L	US-2005/0273600 A1	12-2005	Seeman, El-azar	713/160
*	M	US-2006/0075465 A1	04-2006	Ramanathan et al.	726/001

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,341,164 B1	01-2002	Dilkie et al.	380/278
*	B	US-2002/0166053 A1	11-2002	Wilson, Rodger P.	713/189
*	C	US-2002/0178271 A1	11-2002	Graham et al.	709/229
*	D	US-2002/0184217 A1	12-2002	Bisbee et al.	707/9
*	E	US-6,505,300 B2	01-2003	Chan et al.	713/164
*	F	US-2003/0081790 A1	05-2003	Kallahalla et al.	380/281
*	G	US-2004/0025037 A1	02-2004	Hair, Arthur R.	713/189
*	H	US-2004/0193912 A1	09-2004	Li et al.	713/200
*	I	US-2005/0039034 A1	02-2005	Doyle et al.	713/193
*	J	US-2005/0081029 A1	04-2005	Thornton et al.	713/156
*	K	US-6,915,434 B1	07-2005	Kuroda et al.	713/193
*	L	US-2005/0288961 A1	12-2005	Tabrizi, Majid	705/001
*	M	US-2006/0230437 A1	10-2006	Alexander Boyer et al.	726/004

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,787,175 A	07-1998	Carter, Stephen R.	713/165
*	B	US-2004/0098580 A1	05-2004	DeTreville, John	713/155
*	C	US-2005/0091484 A1	04-2005	Thornton et al.	713/156
*	D	US-2006/0093150 A1	05-2006	Reddy et al.	380/282
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
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